ID.	S	4/12/64						Sh	oot 1	of 1	
FORM PTO-			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 107317-00064			Sheet 1 of 1 SERIAL NO. New Appln			
LIST	r of i		·	TED BY APPLICANT		APPLICANT Kenji MARUYAMA et al			10/821841		
		(Use several sheet	ts if necessary)		FILING DATE April 12, 2004			GROUP 2812			
			U.S. PA	TENT DOCUMENT	S				· ···		
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME		CLASS	SUB- CLASS		FILING		
94	AA	5,995,359	11/30/99	KLEE et al							
Gu	AB	6,258,459 B1	7/10/01	NOGUCHI et al							
	AC									_	
·	AD										
, , , , , , , , , , , , , , , , , , ,	AE										
	AE										
			FOREIGN	PATENT DOCUME	NTS					-	
		DOCUMENT NO.	DATE		COUNTRY		SUB- CLASS	TRANSLATION YES NO PART			
$\mathcal{O}_{\mathcal{U}}$	AG	10-189887	7/21/98	Japan	_			xx		·	
V	АН								. /		
	AI								·		
	LA							_			
	AK										
	AL			·	 						
	1 1									L	
l		OTHER REFEI	RENCES (Includi	ing Author, Title, Dat	te, Pertinent I	Pages, Etc	:.)				
	AM						•				
										_	
	AN										
	-AO										
		l	<u></u>					,			
EXAMINER	Mi	of M.	Luced	L DATE CON	SIDERED C	2, 2	2005	5		4	
*EXAMINE		ital if reference considere	whether or not cite dered. Include copy	ation is in conformance wi of this form with next com	ith MPEP 609; D	raw line thro	ugh citatio	n if not	in		

JUL 2 9 2004 E

FORM PTO-1449

U.S. PARTMENT OF COMMERCE TRABBLENT AND TRADEMARK OFFICE Sheet 1 of 1

ATTY. DOCKET NO.

107317-00064

APPLICANT

MARUYAMA, et al.

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

FILING DATE GROUP
April 12, 2004 2812

U.S. PATENT DOCUMENTS

CONTROL DOCUMENTO								
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE	
M	AA	5,192,723	March 9, 1993	Fujiu et al.			1	
Ou	AB	6,194,753 B1	February 27, 2001	Seon et al.				
GU	AC	2001/0005026 A1	June 28, 2001	Nakamura				
QU	AD	5,514,484	May 7, 1996	Nashimoto				
De	ΑĘ	5,623,439	April 22, 1997	Gotoh et al.				
4	AF							

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE COUNTRY CLASS CLASS		TRANSLATION YES NO PART.					
Ju.	AG	EP 0 957 516 A1	March 24, 1997	Europe		r				
Qu	АН	EP 0795 898 A2	March 10, 1997	Europe		-				
	Al									
	AJ									
	AK									
	AL					_				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

9u	АМ	P.C. Van Buskirk et al., "Common and Unique Aspects of Perovskite Thin Film CVD Processes" Integrated Ferroelectrics, Vol. 21, pgs. 273-289, (1998).
	AN	
	_40-	

EXAMINER Wild W. L	/www.da	DATE CONSIDERED	22,2005
	//		

*EXAMINER: I

Initial (if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

	•	PE	· -					Sh	aat 1	ı of
FORM PTO-144		SE 13 2004 5	U.S. DEPARTMEN	NT OF COMMERCE RADEMARK OFFICE	107317-0006			SERIAL NO 10/821,8		OI
LIST	OF RE	FRENCES	s/ TED BY APPLI	ICANT	APPLICANT MARUYAMA	\ et al				
		& TRAUL		•	FILING DATE	(et ai		GROUP		
		Use several sheets	II necessary)		April 12, 200	14	•	2812		
	·	-	U.S. PATE	ENT DOCUMENT	's		_			
EXAMINER'S INITIALS		DOCUMENT NO.	DATE	NA.	ME	CLASS	SUB- CLASS		ILING DATE	
QU	AA	5,995,359	11/30/1999	Klee et al		T			/	-
94	AB	6,258,459	7/10/2001	Noguchi et al					_	
	AC									
	AD									
	AE			Ţ						
	AF		,					1		
	·•		FOREIGN PA	ATENT DOCUME	NTS		<u>-</u>	<u></u>		
		DOCUMENT NO.	DATE	COUN		CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
	AG									
	АН	,								
	Al.								1	
	AJ								\dashv	
	AK								一	
	AL							_	一十	
								i_		
		OTHER REFER	RENCES (Including	Author, Inte, Da	te, Perunent i	Pages, ⊾to	<u> 2.)</u>			
	AM								<u> </u>	
	AN .							, , , , , , , ,		
	AN				····	·				
	ÃO AO								,	•
].	· ·	<u> </u>							·
	-	****								
EXAMINER	/	1 1/1 1/1	hune da	DATE CON	SIDERED 1 MA.C.A.	1 2	2 20		Þ	

*EXAMINER: Writial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.